

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10575165	VION, PATRICK
	Examiner	Art Unit
	Christopher S Kim	3752

SEARCHED

Class	Subclass	Date	Examiner
239	504, 499, 427, 370, 590.3, 590.5	4/12/08	CK

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner